

Search Notes

Application/Control No.

10/666,078

Examiner

/BINH K. TIEU/

Applicant(s)/Patent under
Reexamination

STEPHENS ET AL.

Art Unit

2614

SEARCHED

Class	Subclass	Date	Examiner
370	259-261	1/14/2008	BKT
	263-267		
	270		
	352-357		
	400-402		
379	202.01		
	205.01		
	207.01		
	215.01		
455	416		
	436, 439		
	442		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
WEST DATABASES SEARCH	1/14/2008	BKT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner